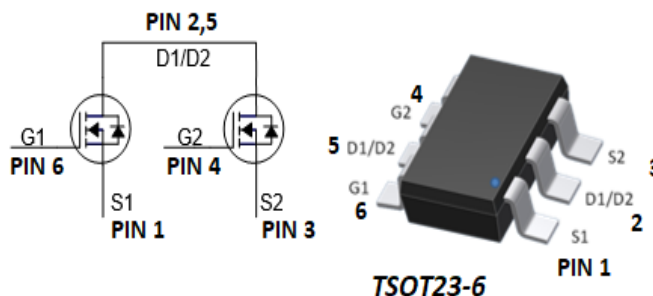


Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor

▪ **Product Summary:**

	N-CH
BVDSS	20 V
$R_{DS(on)} (MAX.) @ V_{GS}=4.5V$	30 mΩ
$R_{DS(on)} (MAX.) @ V_{GS}=2.5V$	51 mΩ
$I_D @ T_A=25^{\circ}C$	5 A

▪ **Pin Description:**



Dual N Channel MOSFET

Rg 100% Tested

Pb-Free Lead Plating & Halogen Free



▪ **ABSOLUTE MAXIMUM RATINGS ($T_A = 25^{\circ}C$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 12	V
Continuous Drain Current	$T_A = 25^{\circ}C$	I_D	5	A
	$T_A = 70^{\circ}C$		4	
Pulsed Drain Current ¹		I_{DM}	20	
Power Dissipation	$T_A = 25^{\circ}C$	P_D	1.3	W
	$T_A = 70^{\circ}C$		0.8	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	$^{\circ}C$

▪ **THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Ambient ³	$R_{\theta JA}$		100	$^{\circ}C/W$

¹Pulse width limited by maximum junction temperature.

²Duty cycle < 1%

³100 $^{\circ}C$ / W when mounted on a 1 in² pad of 2 oz copper.

▪ ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^{\circ}\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage ⁴	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250uA	20			V
Gate Threshold Voltage ⁴	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250uA	0.45	0.75	1.2	
Gate-Body Leakage ⁴	I _{GSS}	V _{DS} = 0V, V _{GS} = ±12V			±100	nA
Zero Gate Voltage Drain Current ⁴	I _{DSS}	V _{DS} = 16V, V _{GS} = 0V			1	uA
		V _{DS} = 16V, V _{GS} = 0V, T _J = 125 °C			10	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = 5V, V _{GS} = 4.5V	5			A
Drain-Source On-State Resistance ^{1,4}	R _{DS(ON)}	V _{GS} = 4.5V, I _D = 5A	15	26	30	mΩ
		V _{GS} = 2.5V, I _D = 4A	20	45	51	
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 5A		7		S
DYNAMIC						
Input Capacitance ⁵	C _{iss}	V _{GS} = 0V, V _{DS} = 10V, f = 1MHz		280		pF
Output Capacitance ⁵	C _{oss}			47		
Reverse Transfer Capacitance ⁵	C _{rss}			38		
Gate Resistance ^{4,5}	R _g	f = 1MHz		1.1		Ω
Total Gate Charge ^{1,2,5}	Q _g	V _{DS} = 10V, V _{GS} = 4.5V, I _D = 5A		6.2		
Gate-Source Charge ^{1,2,5}	Q _{gs}			0.9		
Gate-Drain Charge ^{1,2,5}	Q _{gd}			2.1		
Turn-On Delay Time ^{1,2,5}	t _{d(on)}	V _{DS} = 10V, V _{GS} = 4.5V, I _D = 5A , R _g = 6Ω		12.0		nS
Rise Time ^{1,2,5}	t _r			15.0		
Turn-Off Delay Time ^{1,2,5}	t _{d(off)}			30.0		
Fall Time ^{1,2,5}	t _f			13.0		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Continuous Current	I _S				5	A
Pulsed Current ³	I _{SM}				20	
Forward Voltage ^{1,4}	V _{SD}	I _F = I _S , V _{GS} = 0V			1.2	V

¹Pulse test : Pulse Width $\leq 300\text{ }\mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

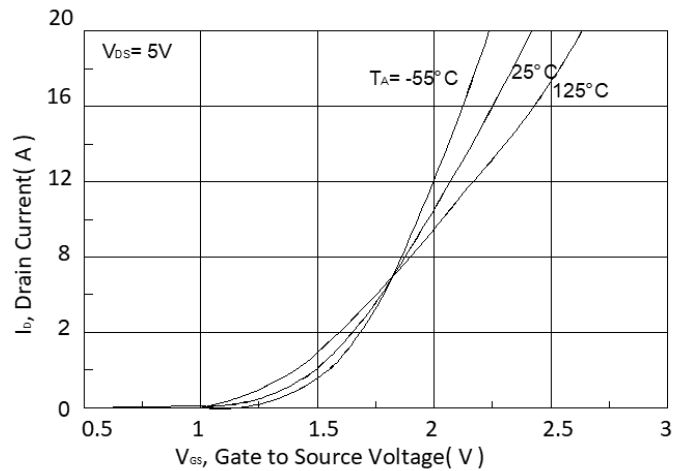
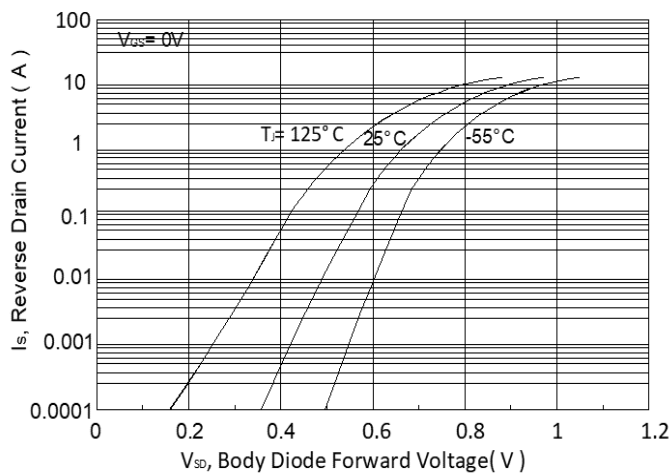
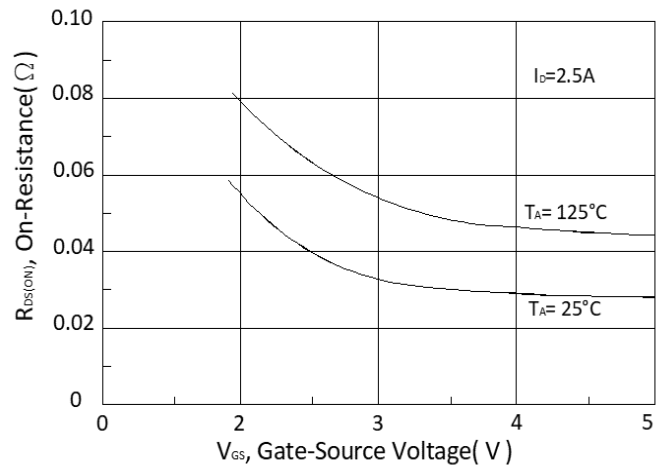
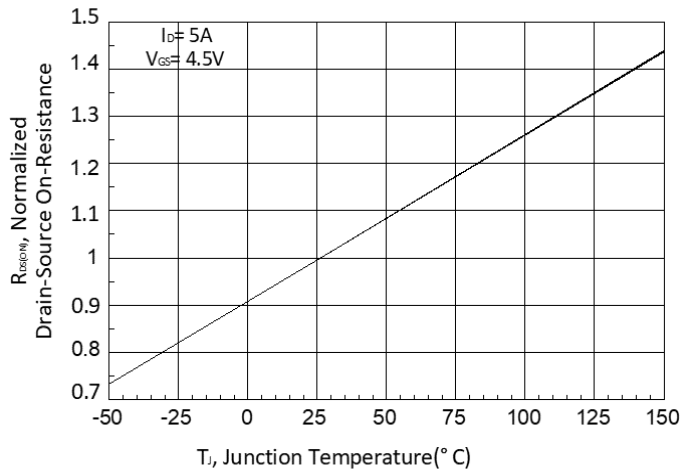
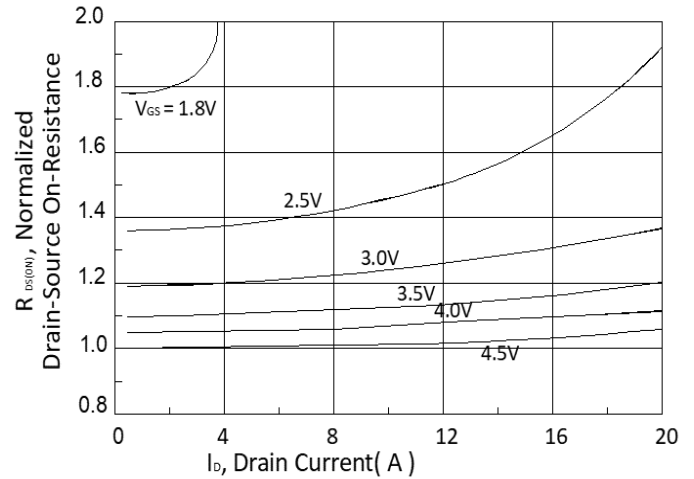
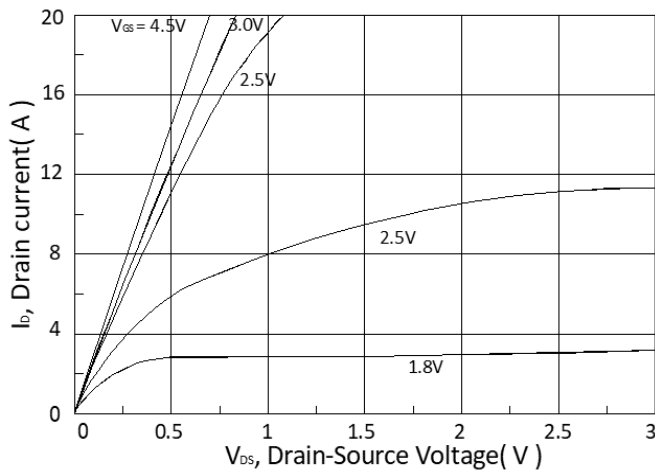
⁴Guarantee by FT test Item

⁵Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.



▪ TYPICAL CHARACTERISTICS



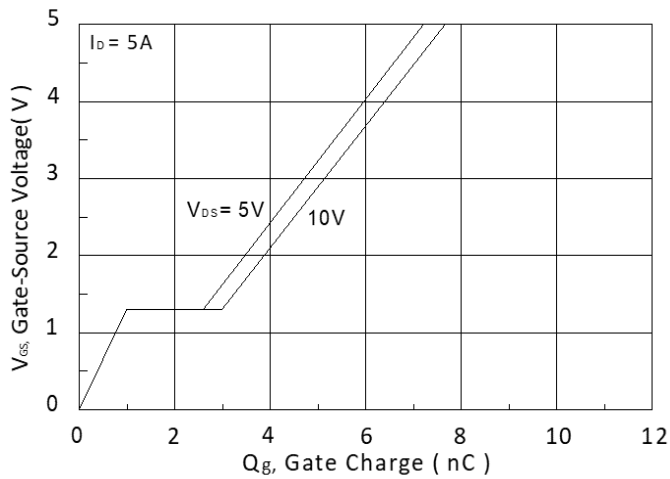


Fig.7 Gate Charge Characteristics

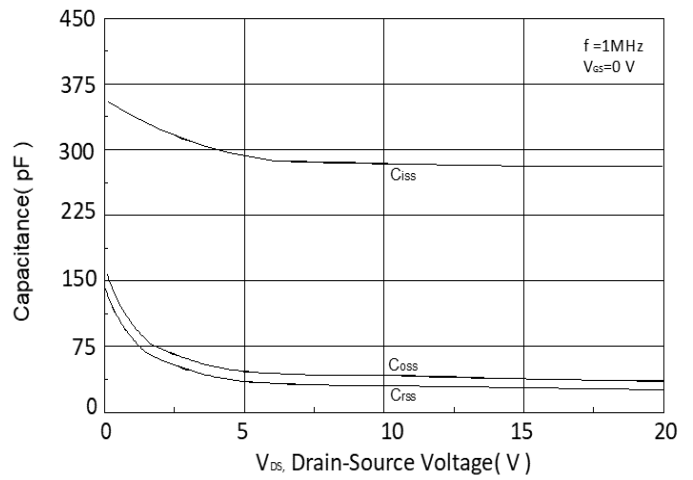


Fig.8 Typical Capacitance Characteristics

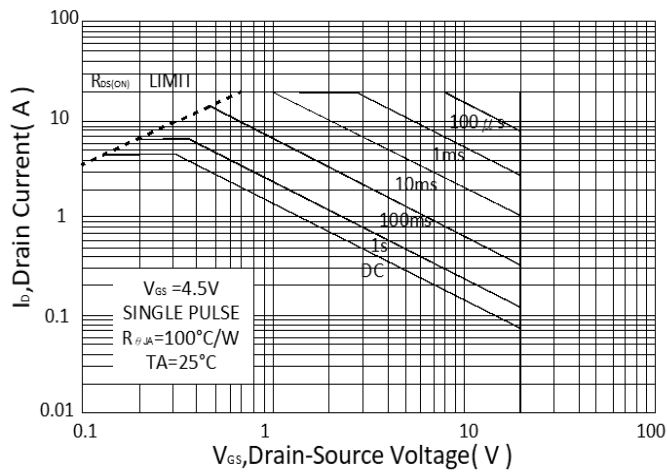


Fig.9. Maximum Safe Operating Area

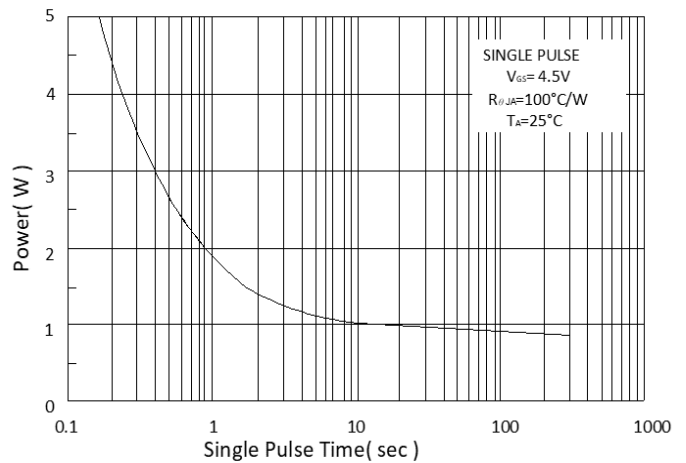


Fig.10. Single Pulse Maximum Power Dissipation

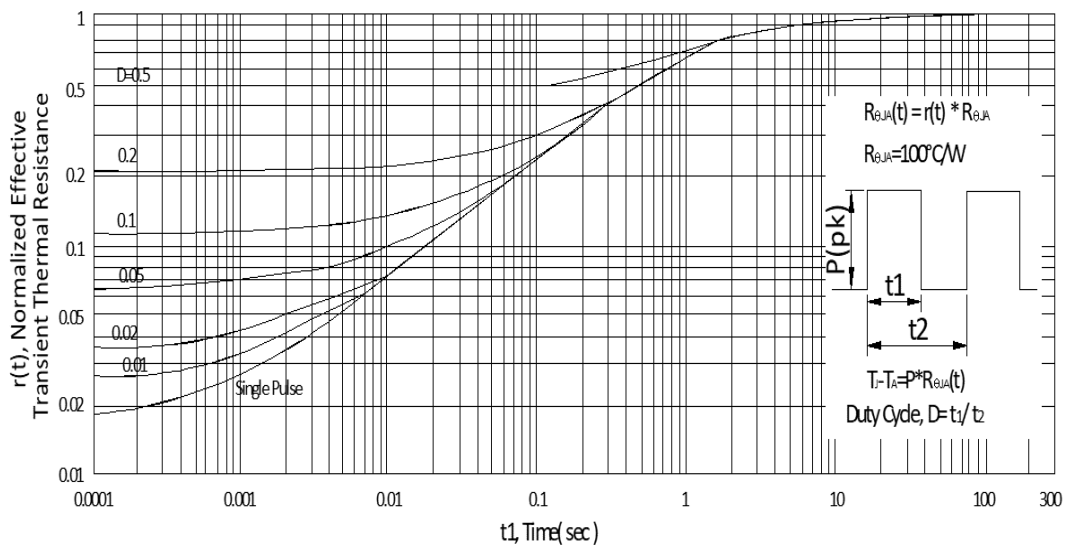
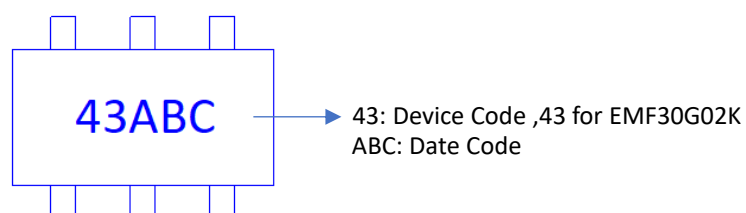


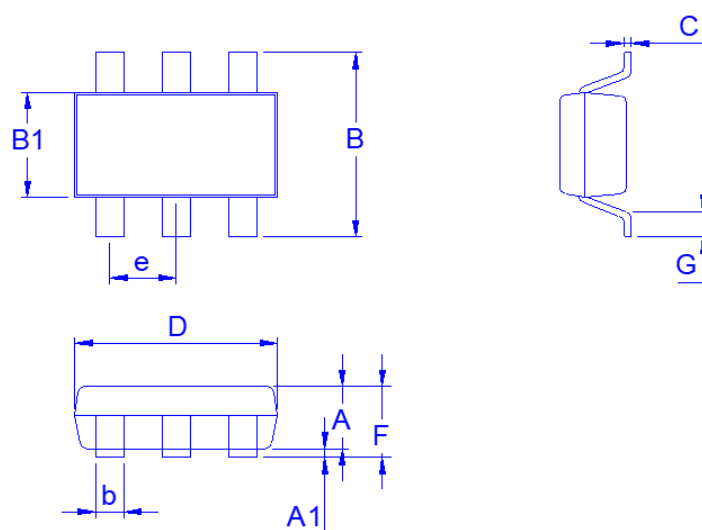
Fig.11. Effective Transient Thermal Impedance

Ordering & Marking Information:

Device Name: EMF30G02K for TSOT23-6

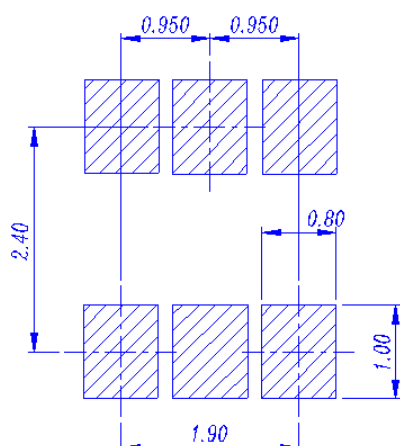


Outline Drawing

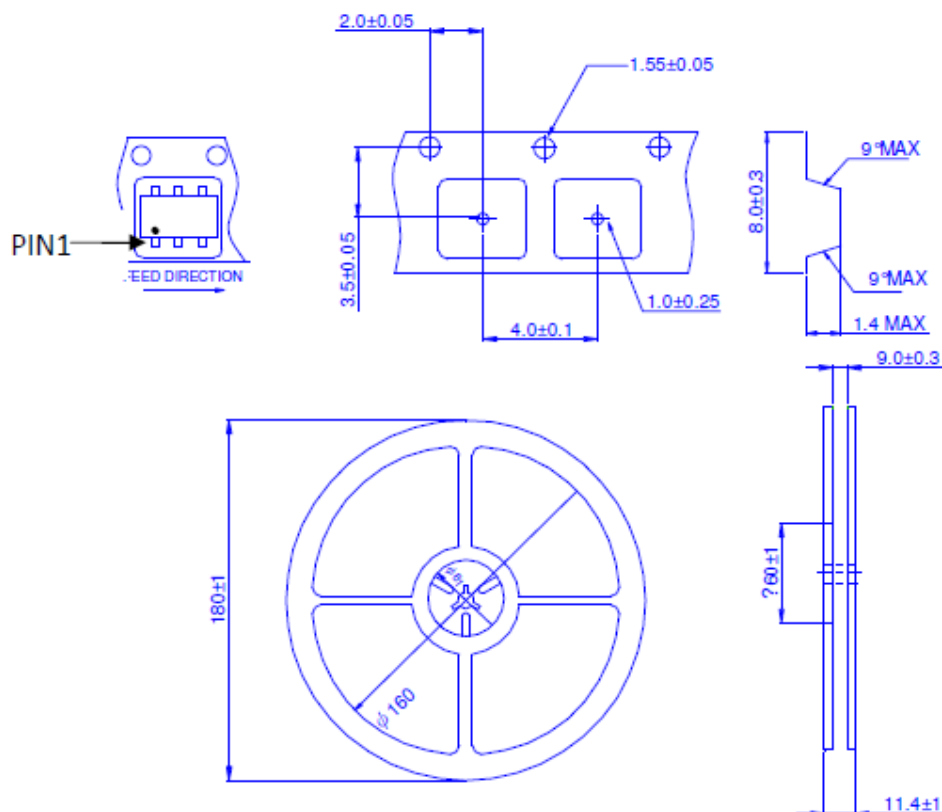


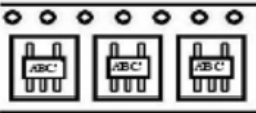
Dimension	A	A1	B	B1	b	C	D	e	F	G
Min.	0.85	0	2.5	1.5	0.3	0.08	2.7		0.85	0.2
Typ.	0.95		2.8	1.6	0.4		2.9	0.95		
Max.	1.25	0.15	3.1	1.7	0.5	0.2	3.1		1.4	0.6

Footprint



◆ Tape&Reel Information: 3000pcs/Reel (Dimension in millimeter)



產品別	TSOT23-6
Reel尺寸	7"
編帶方式	R-Type 
前空格	50
後空格	50
裝箱數	
滿捲數量	3K
捲/內盒比	05:01
內盒滿箱數	15K
內/外箱比	08:01
外箱滿箱數	120K